



Nano
Particle
Technology

Applied Physics, Inc.

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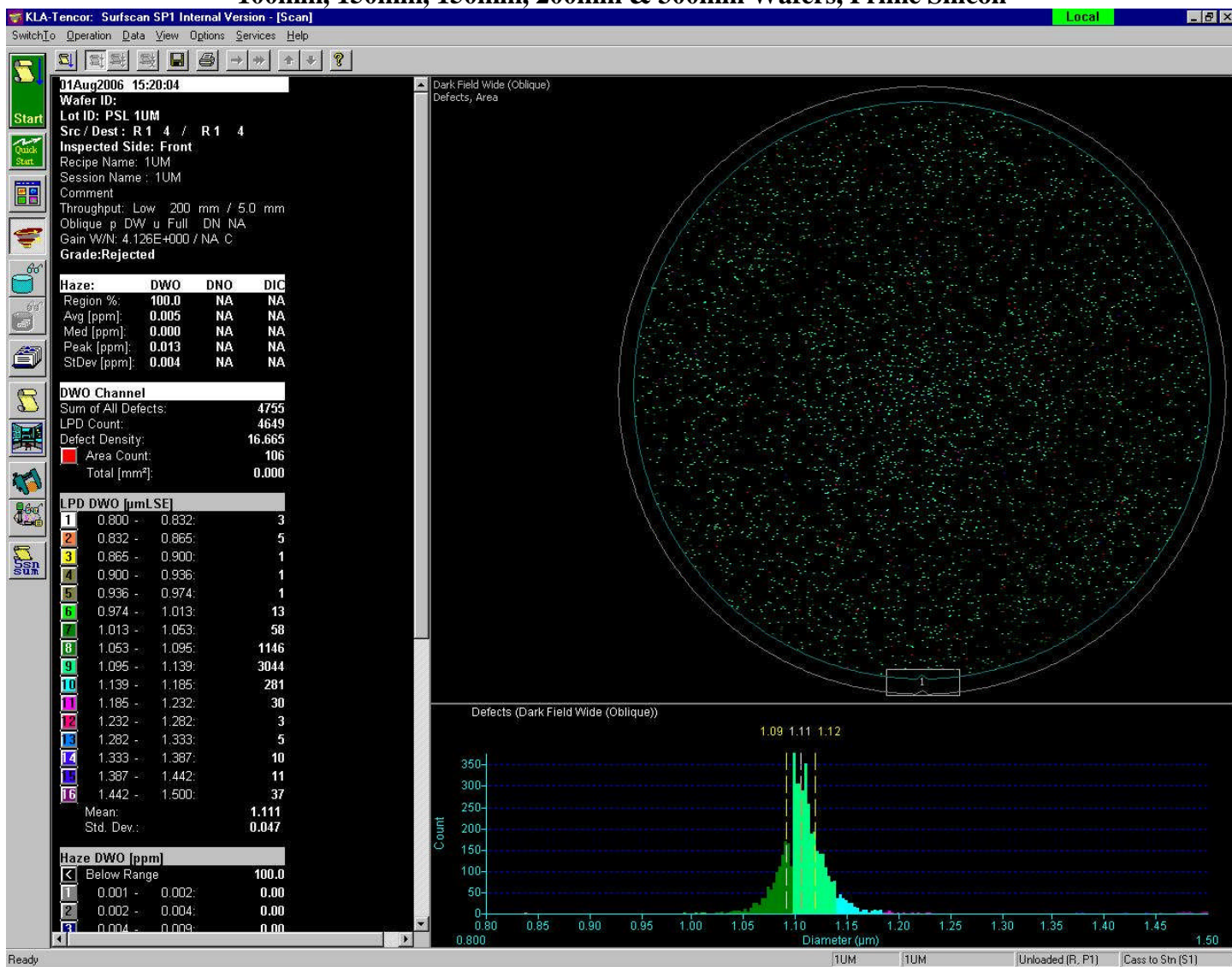
PSL Wafer Calibration Standards: 80nm to 3.040 μ m

Spot Depositions from 80nm to 1.112 μ m

Full Depositions: 80nm to 3.04 μ m

PSL and NIST SRM Particle Size Standards

100mm, 150mm, 150mm, 200mm & 300mm Wafers, Prime Silicon



PSL Wafer Calibration Standards include:

- 1) NIST Traceable PSL Size Certificate based on NIST SRM size calibration
- 2) Post Wafer Scan on SP1 provided with color printout and PSL Size Certificate
- 3) Packaged in Single Wafer Carriers, bagged for shipping cleanliness
- 4) Each wafer standard, Single Wafer Carrier is labeled with deposition specifications
- 5) NIST SRM Sizes of 101.8nm, 269nm and 895nm are also available

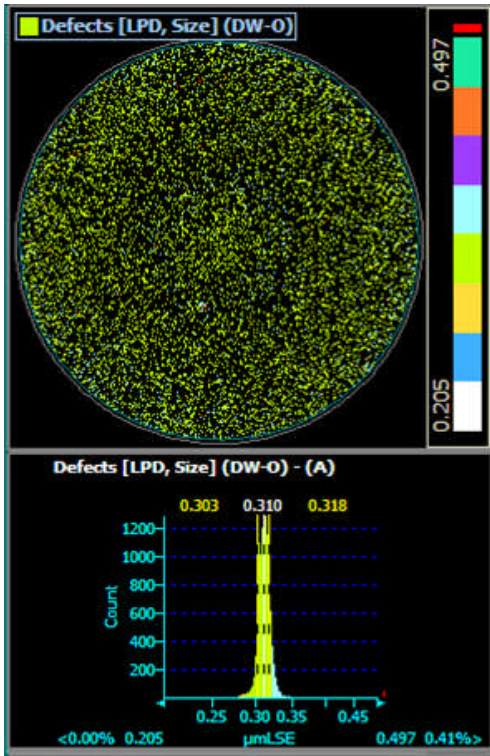


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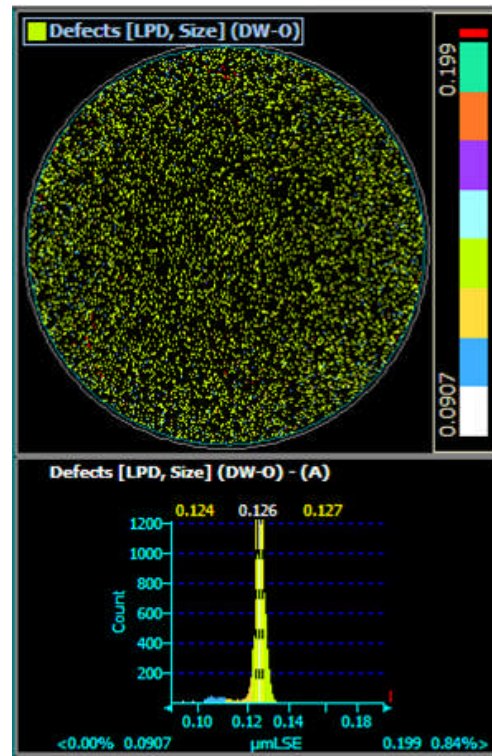
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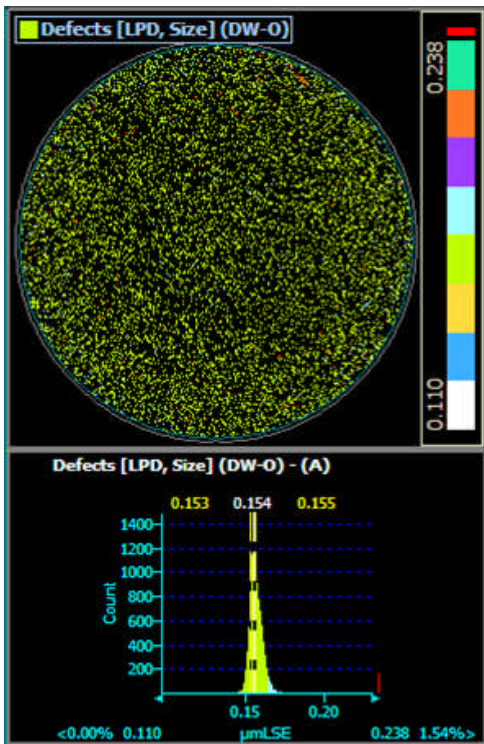


SSIS calibration at 304nm

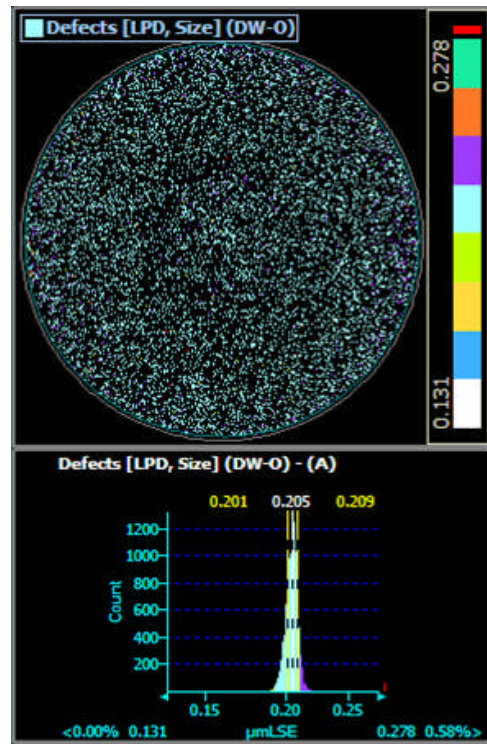


SSIS needs calibration at 126nm

SPOT and FULL WAFER PSL DEPOSITIONS



SSIS close to calibration at 155nm



SSIS close to calibration @ 204nm

SPOT and FULL WAFER PSL DEPOSITIONS

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